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|-----------------------------------|--|--------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination YU ET AL. | |
| | | Examiner Thuy V. Tran | Art Unit 2821 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------------------|----------------|
| | A | US-2004/0155853 A1 | 08-2004 | Lin, Yung-Lin | 345/102 |
| | B | US-2004/0061708 A1 | 04-2004 | Oh, Jang Geun | 345/690 |
| | C | US-2003/0151601 A1 | 08-2003 | Chung et al. | 345/211 |
| | D | US-6,762,742 | 07-2004 | Moon et al. | 345/102 |
| | E | US-6,396,217 | 05-2002 | Weindorf, Paul Fredrick Luther | 315/169.1 |
| | F | US-5,786,801 | 07-1998 | Ichise, Atsushi | 345/102 |
| | G | US-5,272,327 | 12-1993 | Mitchell et al. | 250/205 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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